

IGBT

TRENCHSTOP™ IGBT4 Low Power Chip IGC99T120T8RL

Data Sheet

Industrial Power Control

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TRENCHSTOPTM IGBT4 Low Power Chip

Features:

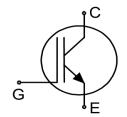
- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

Recommended for:

Low / medium power modules

Applications:

Low / medium power drives



Chip Type V _{CE}	I Cn ¹	Die Size	Package
IGC99T120T8RL 1200	/ 100A	9.5mm x 10.39mm	Sawn on foil

Mechanical Parameters

Die size		9.5 x 10.35		
Emitter pad size		See chip drawing	mm²	
Gate pad size		1.31 x 0.811	mm	
Area total		98.71		
Thickness		115	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	258		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond	oond Al, ≤500µm			
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
01	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2 s <6 months		
Storage environment	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or humidity <25%RH, temperature 17°C – 25°C, <6		

L7683P, L7683V 3 Rev. 2.1, 20.08.2015

¹ Nominal collector current at T_C =100°C for chip packaged in power modules, see application example cited on page 5.



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _{vj} =25°C	V _{CE}	1200	V
DC collector current, limited by $T_{\rm vj\;max}^{\;\;2}$	I _C	-	Α
Pulsed collector current, t_p limited by $T_{vj \max}$ 3	I _{C,puls}	300	Α
Gate-emitter voltage	V_{GE}	±20	V
Operating junction temperature	$T_{\rm vj}$	-40 +175	°C
Short circuit data $^{3/4}$ V_{GE} =15V, V_{CC} =800V, T_{vj} =150°C	t _{sc}	10	μs

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol	Conditions	Value			Unit
Faranietei		Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V, I_{C} =3.8mA	1200	ı	ı	
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =100A	1.53	1.75	1.97	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =3.8mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V, V _{GE} =0V	-	-	1.3	μA
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$	-	-	120	nA
Integrated gate resistor	r _G			7.5		Ω

Electrical Characteristics ³

Parameter	Symbol Conditions		Value			Unit
raiametei	Symbol	Conditions	min.	typ.	max.	Onit
Collector-emitter saturation voltage	V _{CEsat}	V_{GE} =15V, I_{C} =100A, T_{vj} =150°C	-	2.1	-	V
Input capacitance	C _{ies}	$V_{\rm CE}$ =25V,	1	6300	1	ηE
Reverse transfer capacitance	C _{res}	$V_{ m GE}$ =0V, f =1MHz $T_{ m vj}$ =25°C	ı	270	-	pF

² Depending on thermal properties of assembly.

³ Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristics

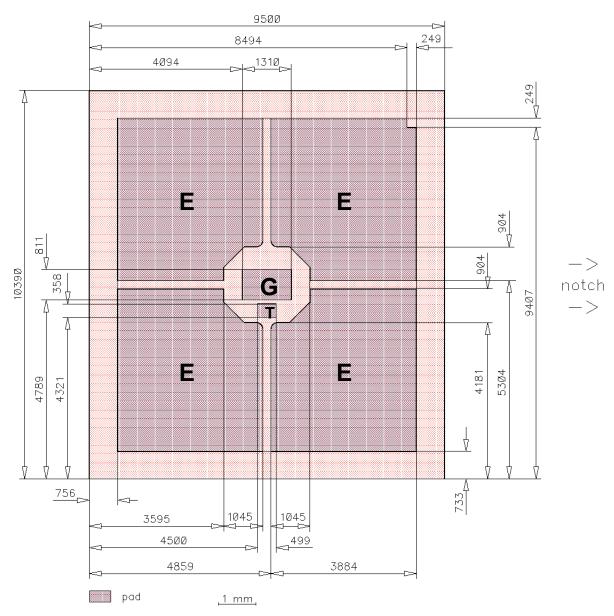
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FP100R12KT4_B11	Rev. 3.0
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Chip Drawing





E = Emitter

G = Gate

T = Test pad do not contact



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	18.02.2015
2.1	Update disclaimer	20.08.2015

Relevant App	lication Notes



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